ETS’09
Tutorials

Monday, May, 25

9:00 – 13:00	**TTEP** **Tutorial 1** Advanced Topics and Recent Advances in Silicon Debug and Diagnosis

lunch

14:30 – 17:30	**TTEP** **Tutorial 1** Advanced Topics and Recent Advances in Silicon Debug and Diagnosis
20:00 – 22:00	**Welcome Reception**

ETS'09 Program At a Glance

Tuesday, May, 26

8:30 – 10:30	**Plenary Opening Keynote Addresses**		
10:30 – 11:30	Session 2 - **POSTER I** and Coffee Break		
11:30 – 13:00	Session 3A **Internal Testing of Mixed-Signal Cores**	Session 3B **Debug and Validation**	Session 3C **Vendor 1**
	lunch		
14:30 – 16:00	Session 4A **Power Issues During Test**	Session 4B **Self-test and Test Throughput**	Session 4C **Vendor 2**
16:00 – 17:00	Session 5 - **POSTER II** and Coffee Break		
17:00 – 18:00	Session 6A **On-line Testing**	Session 6B **Vendor 3**	
18:00 – 19:30	Session 7A **Panel 1** **Yield, Reliability and Variability in the Nano-Era**	Session 7B **Panel 2** **Extended Diagnosis Req. in Automotive Applications**	

ETS’09 Program At a Glance

Wednesday, May, 27

9:00 – 10:30	Session 8A **Advanced Testing Mem., Power Trans. Microfluidic Syst.**	Session 8B **Recent Advances in ATPG**	Session 8C **Student’s Forum**
10:30 – 11:30	Session 9 - Coffee Break and **STUDENT’S POSTERS**		
11:30 – 13:00	Session 10A **Advanced External Test of Mixed-Signal Cores**	Session 10B **Diagnosis and Dependability Analysis**	Session 10C **Special** **Soft Errors in Electronic Systems**

lunch

14:30 – 15:30	Session 11A **Emb. Tutorial 1** **Switching Noise and Process Var. Challenges in Delay Testing**	Session 11B **Emb. Tutorial 2** **Test Challenges and Solutions in TSV-Based 3D Stacked ICs**
16:00 – 23:00	**Social Program**	

ETS'09 Program At a Glance

Thursday, May, 28

9:00 – 10:30	Session 12A **Impact of Nanometer Technol. in the Testing Methodology**	Session 12B **DfT and Embedded Test**
10:30 – 11:30	Session 13 - **POSTER III** and Coffee Break	
11:30 – 12:30	Session 14A **Emb. Tutorial 3** **Ensuring High Testability without Degrading Security**	Session 14B **Emb. Tutorial 4** **On-chip Delay Measurem. Tech. for Production Test – from D to A**
12:30 – 13:00	Session 15 - **Plenary Closing**	

lunch

ETS'09
Fringe Workshop

Friday, May, 29

9:00 – 13:00	**Lp on TR** Impact of Low-Power design on Test and Reliability

lunch

14:30 – 17:00	**LP on TR** Impact of Low-Power design on Test and Reliability